

STB36NF03L

N-CHANNEL 30V - 0.015 Ω - 36A D²PAK LOW GATE CHARGE STripFETTM POWER MOSFET

PRELIMINARY DATA

TYPE	V _{DSS}	V _{DSS} R _{DS(on)}	
STB36NF03L	30 V	< 0.02 Ω	36 A

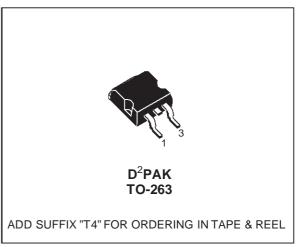
- TYPICAL R_{DS(on)} = 0.015Ω
- TYPICAL Q_q = 18 nC @ 10V
- OPTIMAL R_{DS(on)} x Q_g TRADE-OFF
- CONDUCTION LOSSES REDUCED
- SWITCHING LOSSES REDUCED

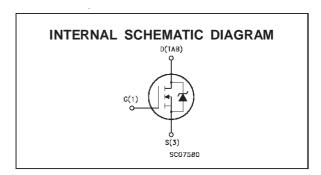
DESCRIPTION

This application specific Power Mosfet is the third generation of STMicroelectronics unique "Single Feature SizeTM" strip-based process. The resulting transistor shows the best trade-off between on-resistance and gate charge. When used as high and low side in buck regulators, it gives the best performance in terms of both conduction and switching losses. This is extremely important for motherboards where fast switching and high efficiency are of paramount importance.

APPLICATIONS

 SPECIFICALLY DESIGNED AND OPTIMISED FOR HIGH EFFICIENCY CPU CORE DC/DC CONVERTERS





ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source Voltage (V _{GS} = 0)	30	V
V_{DGR}	Drain- gate Voltage ($R_{GS} = 20 \text{ k}\Omega$)	30	V
V _{GS}	Gate-source Voltage	± 20	V
I _D	Drain Current (continuous) at T _c = 25 °C	36	А
I _D	Drain Current (continuous) at T _c = 100 °C	25	А
I _{DM} (•)	Drain Current (pulsed)	144	А
P _{tot}	Total Dissipation at T _c = 25 °C	75	W
	Derating Factor	0.5	W/°C
T _{stg}	Storage Temperature	-65 to 175	°C
Tj	Max. Operating Junction Temperature	175	°C

(•) Pulse width limited by safe operating area

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THERMAL DATA

J 5 '	j-amb	Thermal	Resistance	Junction-case Junction-ambient	Max Max	2 62.5		°C/W
7	Τ _I	Maximun	n Lead Temp	erature For Solderir	ng Purpose	300)	°C

ELECTRICAL CHARACTERISTICS ($T_{case} = 25$ ^{o}C unless otherwise specified)

OFF

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source Breakdown Voltage	$I_D = 250 \ \mu A$ $V_{GS} = 0$	30			V
I _{DSS}	Zero Gate Voltage Drain Current (V _{GS} = 0)	$V_{DS} = Max Rating$ $V_{DS} = Max Rating$ $T_c = 125$ °C			1 10	μΑ μΑ
I _{GSS}	Gate-body Leakage Current (V _{DS} = 0)	V _{GS} = ± 20 V			± 100	nA

ON (*)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}$ $I_D = 250 \mu A$	1			V
R _{DS(on)}	Static Drain-source On Resistance	$V_{GS} = 10V$ $I_{D} = 18 A$ $V_{GS} = 5V$ $I_{D} = 9 A$		0.015 0.026	0.020 0.035	Ω
I _{D(on)}	On State Drain Current	$V_{DS} > I_{D(on)} \times R_{DS(on)max}$ $V_{GS} = 10 \text{ V}$	36			А

DYNAMIC

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
g _{fs} (*)	Forward Transconductance	$V_{DS} > I_{D(on)} \times R_{DS(on)max}$ $I_D = 18 A$		20		S
C _{iss} C _{oss} C _{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25 \text{ V}$ f = 1 MHz $V_{GS} = 0$		750 270 60		pF pF pF

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ELECTRICAL CHARACTERISTICS (continued)

SWITCHING ON

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t _{d(on)} t _r	Turn-on Delay Time Rise Time	$\begin{array}{cccccccccccccccccccccccccccccccccccc$		16 200		ns ns
$egin{array}{c} Q_g \ Q_{gs} \ Q_{gd} \end{array}$	Total Gate Charge Gate-Source Charge Gate-Drain Charge	$V_{DD} = 24 \text{ V } I_{D} = 32 \text{ A } V_{GS} = 10 \text{ V}$		18 3 5	21	nC nC nC

SWITCHING OFF

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t _{d(off)} t _f	Turn-off Delay Time Fall Time	$\begin{array}{cccccccccccccccccccccccccccccccccccc$		35 40		ns ns

SOURCE DRAIN DIODE

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
I _{SD} I _{SDM} (•)	Source-drain Current Source-drain Current (pulsed)				36 144	A A
V _{SD} (*)	Forward On Voltage	$I_{SD} = 36 \text{ A} V_{GS} = 0$			1.5	V
t _{rr}	Reverse Recovery Time	$I_{SD} = 36 \text{ A}$		38		ns
Q _{rr}	Reverse Recovery	(see test circuit, fig. 5)		30		nC
I _{RRM}	Charge Reverse Recovery Current			1.6		A

^(*) Pulsed: Pulse duration = 300 μs, duty cycle 1.5 %
(•) Pulse width limited by safe operating area

Fig. 1: Unclamped Inductive Load Test Circuit

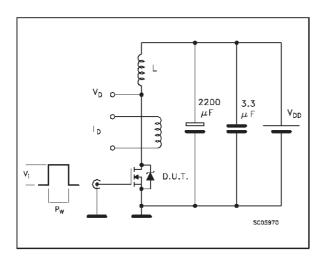


Fig. 3: Switching Times Test Circuits For Resistive Load

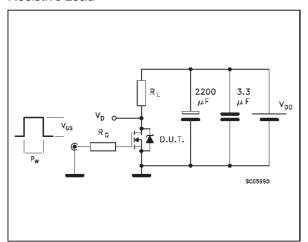


Fig. 5: Test Circuit For Inductive Load Switching And Diode Recovery Times

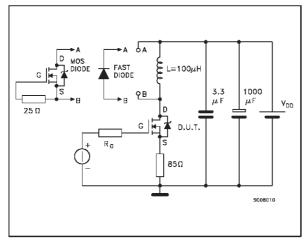


Fig. 2: Unclamped Inductive Waveform

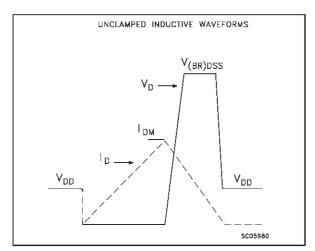
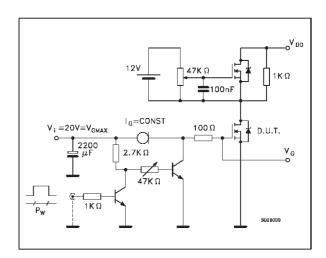


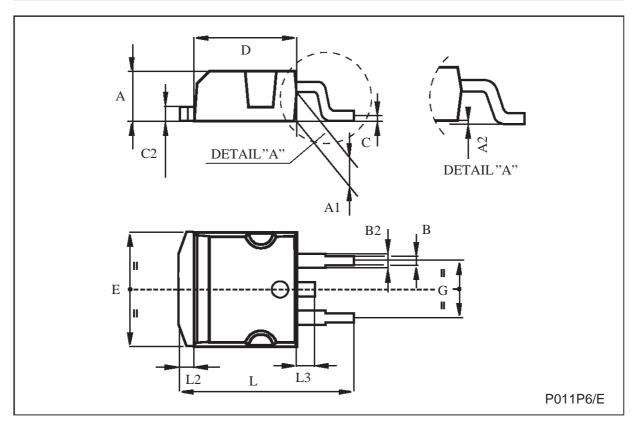
Fig. 4: Gate Charge test Circuit



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TO-263 (D²PAK) MECHANICAL DATA

DIM.	mm			inch			
Dim.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	
А	4.4		4.6	0.173		0.181	
A1	2.49		2.69	0.098		0.106	
В	0.7		0.93	0.027		0.036	
B2	1.14		1.7	0.044		0.067	
С	0.45		0.6	0.017		0.023	
C2	1.21		1.36	0.047		0.053	
D	8.95		9.35	0.352		0.368	
E	10		10.4	0.393		0.409	
G	4.88		5.28	0.192		0.208	
L	15		15.85	0.590		0.624	
L2	1.27		1.4	0.050		0.055	
L3	1.4		1.75	0.055		0.068	



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